

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/614,384 | Applicant(s)/Patent Under Reexamination HILLIARD ET AL. | |
| | Examiner Anjan K Deb | Art Unit 2858 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-5,469,156 | 11-1995 | Kogure, Makoto | 340/870.38 |
| * | B | US-4,568,937 | 02-1986 | Clark, Michael A. G. | 340/939 |
| * | C | US-4,263,549 | 04-1981 | Toppeto, Alphonse A. | 324/127 |
| * | D | US-5,621,314 | 04-1997 | Beck et al. | 324/179 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | IEEE 100. The Authoritative Dictionary of IEEE Standards Terms (pages 287 and 339). Seventh Edition. Publisher IEEE Press 2000. ISBN 0-7381-2601-2 |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.